



40V N-Channel NexFET™ Power MOSFETs

Check for Samples: CSD18501Q5A

FEATURES

- Ultralow Q_q and Q_{qd}
- Low Thermal Resistance
- Avalanche Rated
- Logic Level
- Pb Free Terminal Plating
- RoHS Compliant
- Halogen Free
- SON 5-mm × 6-mm Plastic Package

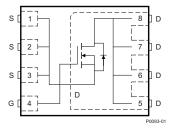
APPLICATIONS

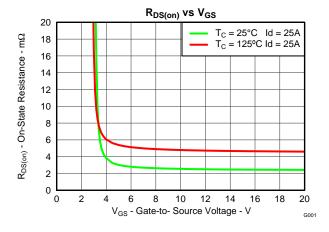
- DC-DC Conversion
- Secondary Side Synchronous Rectifier
- Battery Motor Control

DESCRIPTION

The NexFET™ power MOSFET has been designed to minimize losses in power conversion applications.







PRODUCT SUMMARY

	/alues at 25°C therwise stated	TYPICAL VA	UNIT	
V_{DS}	Drain to Source Voltage	40	V	
Q_g	Gate Charge Total (4.5V)	20	nC	
Q_{gd}	Gate Charge Gate to Drain	te Charge Gate to Drain 5.9		
D	Drain to Source On Resistance	$V_{GS} = 4.5V$	3.3	mΩ
NDS(on)	R _{DS(on)} Drain to Source On Resistance		V _{GS} = 10V 2.5	
$V_{GS(th)}$	Threshold Voltage	1.8	V	

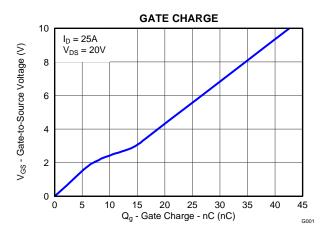
ORDERING INFORMATION

Device	Package	Media	Qty	Ship
CSD18501Q5A	SON 5-mm × 6-mm Plastic Package	13-Inch Reel	2500	Tape and Reel

ABSOLUTE MAXIMUM RATINGS

T _A = 2	5°C unless otherwise stated	VALUE	UNIT	
V_{DS}	Drain to Source Voltage	40	٧	
V_{GS}	Gate to Source Voltage	±20	٧	
	Continuous Drain Current (Package limited), T _C = 25°C	100	•	
I _D	Continuous Drain Current (Silicon limited), $T_C = 25$ °C	155	A	
	Continuous Drain Current, T _A = 25°C ⁽¹⁾	22	Α	
I_{DM}	Pulsed Drain Current, T _A = 25°C ⁽²⁾	142	Α	
P _D	Power Dissipation ⁽¹⁾	3.1	W	
T _J , T _{STG}	Operating Junction and Storage Temperature Range	-55 to 150	°C	
E _{AS}	E_{AS} Avalanche Energy, Single Pulse $I_D = 68A$, $L = 0.1 \text{mH}$, $R_G = 25\Omega$		mJ	

- (1) Typical $R_{\theta JA} = 40^{\circ} C/W$ on a 1-inch², 2-oz. Cu pad on a 0.06-inch thick FR4 PCB.
- (2) Pulse duration ≤300µs, duty cycle ≤2%



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These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

ELECTRICAL CHARACTERISTICS

 $(T_A = 25^{\circ}C \text{ unless otherwise stated})$

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Static Cl	naracteristics					
BV _{DSS}	Drain to Source Voltage	$V_{GS} = 0V, I_D = 250\mu A$	40			V
I _{DSS}	Drain to Source Leakage Current	V _{GS} = 0V, V _{DS} = 32V			1	μΑ
I _{GSS}	Gate to Source Leakage Current	V _{DS} = 0V, V _{GS} = 20V			100	nA
$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1.4	1.8	2.3	V
_	Dunin to Course On Bonintones	V _{GS} = 4.5V, I _D = 25A		3.3	4.3	mΩ
R _{DS(on)}	Drain to Source On Resistance	V _{GS} = 10V, I _D = 25A		2.5	3.2	mΩ
9 _{fs}	Transconductance	V _{DS} = 20V, I _D = 25A		142		S
Dynamic	: Characteristics					
C _{iss}	Input Capacitance			3200	3840	pF
C _{oss}	Output Capacitance	$V_{GS} = 0V, V_{DS} = 20V,$ f = 1MHz		725	870	pF
C _{rss}	Reverse Transfer Capacitance	1 - 10012		18	23	pF
R_G	Series Gate Resistance			1.2	2.4	Ω
Qg	Gate Charge Total (4.5V)			20	24	nC
Qg	Gate Charge Total (10V)			42	50	
Q _{gd}	Gate Charge Gate to Drain	$V_{DS} = 20V, I_D = 25A$		5.9		nC
Q _{gs}	Gate Charge Gate to Source			8.1		nC
Q _{g(th)}	Gate Charge at Vth			5.7		nC
Q _{oss}	Output Charge	V _{DS} = 20V, V _{GS} = 0V		48		nC
t _{d(on)}	Turn On Delay Time			4.7		ns
t _r	Rise Time	$V_{DS} = 20V, V_{GS} = 10V,$		10		ns
t _{d(off)}	Turn Off Delay Time	$I_{DS} = 25A$, $R_G = 2\Omega$		20		ns
t _f	Fall Time			3.4		ns
Diode Cl	haracteristics					
V _{SD}	Diode Forward Voltage	I _{DS} = 25A, V _{GS} = 0V		0.8	1	V
Q _{rr}	Reverse Recovery Charge	V 20V I 25A di/dt 200A/:		21		nC
t _{rr}	Reverse Recovery Time	V_{DS} = 20V, I_F = 25A, di/dt = 300A/ μ s		40		ns

THERMAL CHARACTERISTICS

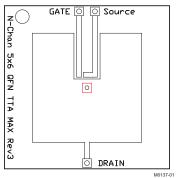
 $(T_A = 25^{\circ}C \text{ unless otherwise stated})$

	PARAMETER	MIN	TYP	MAX	TINU
$R_{\theta JC}$	Thermal Resistance Junction to Case ⁽¹⁾			1	°C/W
$R_{\theta JA}$	Thermal Resistance Junction to Ambient (1)(2)			50	°C/W

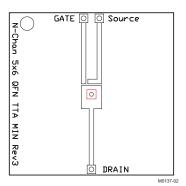
 $R_{\theta JC}$ is determined with the device mounted on a 1-inch² (6.45-cm²), 2-oz. (0.071-mm thick) Cu pad on a 1.5-inch x 1.5-inch (3.81-cm x 3.81-cm), 0.06-inch (1.52-mm) thick FR4 PCB. $R_{\theta JC}$ is specified by design, whereas $R_{\theta JA}$ is determined by the user's board design. Device mounted on FR4 material with 1-inch² (6.45-cm²), 2-oz. (0.071-mm thick) Cu.

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Max $R_{\theta JA} = 50^{\circ} C/W$ when mounted on 1 inch² (6.45-cm²) of 2-oz. (0.071-mm thick) Cu.



Max $R_{\theta JA} = 122^{\circ} C/W$ when mounted on a minimum pad area of 2-oz. (0.071-mm thick) Cu.

TYPICAL MOSFET CHARACTERISTICS

(T_A = 25°C unless otherwise stated)

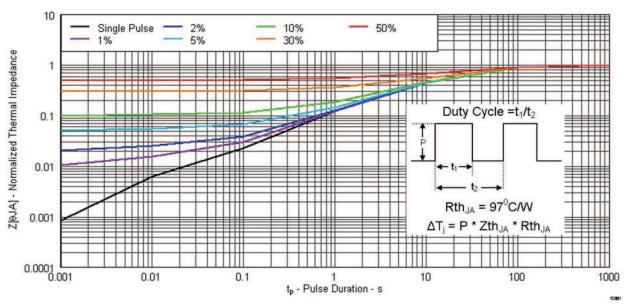


Figure 1. Transient Thermal Impedance



TYPICAL MOSFET CHARACTERISTICS (continued)

 $(T_A = 25^{\circ}C \text{ unless otherwise stated})$

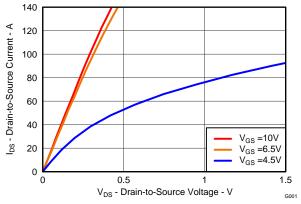


Figure 2. Saturation Characteristics

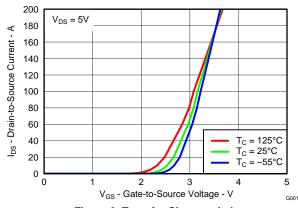


Figure 3. Transfer Characteristics

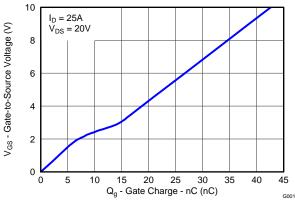


Figure 4. Gate Charge

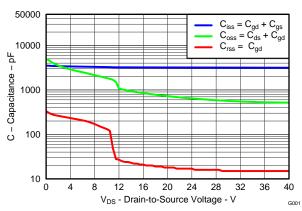


Figure 5. Capacitance

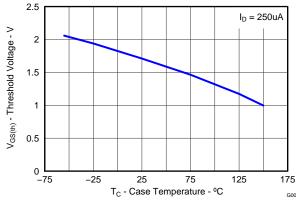


Figure 6. Threshold Voltage vs. Temperature

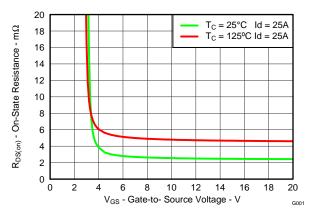


Figure 7. On-State Resistance vs. Gate-to-Source Voltage



TYPICAL MOSFET CHARACTERISTICS (continued)

 $(T_A = 25^{\circ}C \text{ unless otherwise stated})$

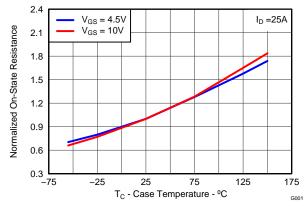


Figure 8. Normalized On-State Resistance vs. Temperature

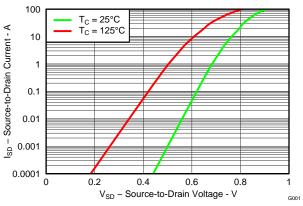


Figure 9. Typical Diode Forward Voltage

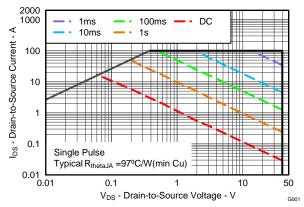


Figure 10. Maximum Safe Operating Area

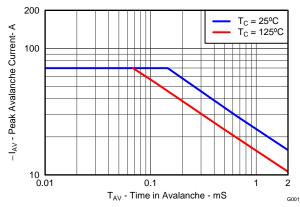


Figure 11. Single Pulse Unclamped Inductive Switching

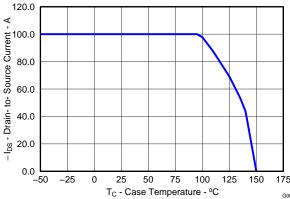
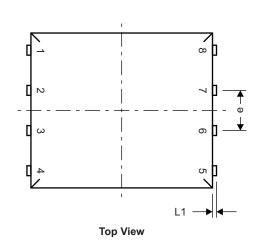


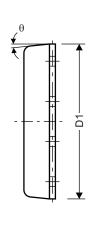
Figure 12. Maximum Drain Current vs. Temperature



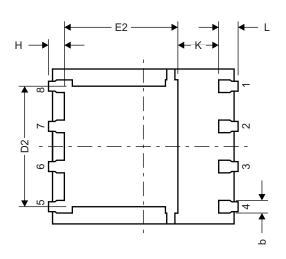
MECHANICAL DATA

Q5A Package Dimensions

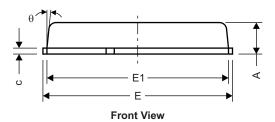




Side View



Bottom View

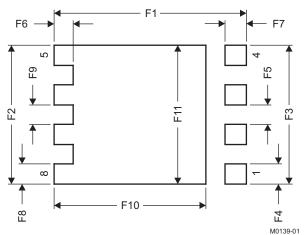


M0135-01

DIM	MILLIMETERS						
DIM	MIN	NOM	MAX				
A	0.90	1.00	1.10				
b	0.33	0.41	0.51				
С	0.20	0.25	0.34				
D1	4.80	4.90	5.00				
D2	3.61	3.81	4.02				
Е	5.90	6.00	6.10				
E1	5.70	5.75	5.80				
E2	3.38	3.58	3.78				
е	1.17	1.27	1.37				
Н	0.41	0.56	0.71				
K	1.10						
L	0.51	0.61	0.71				
L1	0.06	0.13	0.20				
θ	0°		12°				



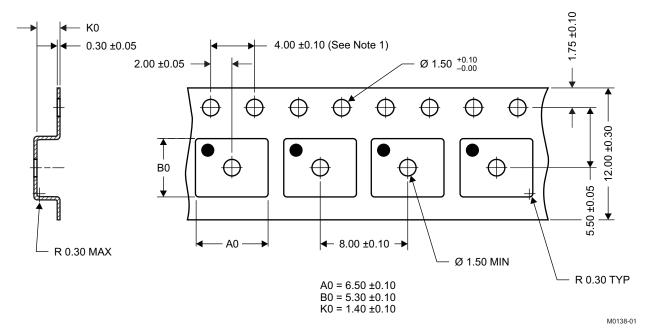
Figure 13. Recommended PCB Pattern



DIM	MILLIM	IETERS	INCHES		
	MIN	MAX	MIN	MAX	
F1	6.205	6.305	0.244	0.248	
F2	4.46	4.56	0.176	0.18	
F3	4.46	4.56	0.176	0.18	
F4	0.65	0.7	0.026	0.028	
F5	0.62	0.67	0.024	0.026	
F6	0.63	0.68	0.025	0.027	
F7	0.7	0.8	0.028	0.031	
F8	0.65	0.7	0.026	0.028	
F9	0.62	0.67	0.024	0.026	
F10	4.9	5	0.193	0.197	
F11	4.46	4.56	0.176	0.18	

For recommended circuit layout for PCB designs, see application note SLPA005 – Reducing Ringing Through PCB Layout Techniques.

Q5A Tape and Reel Information



Notes:

- 1. 10-sprocket hole-pitch cumulative tolerance ±0.2
- 2. Camber not to exceed 1mm in 100mm, noncumulative over 250mm
- 3. Material: black static-dissipative polystyrene
- 4. All dimensions are in mm (unless otherwise specified)
- 5. A0 and B0 measured on a plane 0.3mm above the bottom of the pocket

SLPS319A – JUNE 2012 – REVISED JUNE 2012



REVISION HISTORY

Cł	hanges from Original (June 2012) to Revision A	Page
•	Added "Typical Values at 25°C unless otherwise stated" to the Product Summary table	1



PACKAGE OPTION ADDENDUM

2-Jul-2012

PACKAGING INFORMATION

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins	Package Qty	Eco Plan ⁽²⁾	Lead/ Ball Finish	MSL Peak Temp ⁽³⁾	Samples (Requires Login)
CSD18501Q5A	ACTIVE	SON	DQJ	8	2500	Pb-Free (RoHS Exempt)	CU SN	Level-1-260C-UNLIM	

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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